Pre-Production Test Plan

Electromagnetic Interference

And Susceptability Tests

High Level Multicoder

Model HDA4M-839

Manufactured By

Fifth Dimension, Inc.

Princeton, New Jersey

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#### COMPONENT TYPE QUALIFICATION PROCEDURE

#### PART III - ELECTROMAGNETIC INTERFERENCE

#### AND SUSCEPTIBILITY TESTS

1.0 GENERAL. This part of the document contains procedures for measuring electromagnetic interference and for determining susceptibility in accordance with Electromagnetic Interference Specifications MIL-I-26600 and MSC-ASPO-EMI-10A. The tests are to be conducted on Fifth Dimension Multicoder, Model No. HDA4M-839.

The primary purpose of these tests is to determine that the levels and frequencies of Conducted and Radiated Interference emanating from the component are within established limits; and to establish the susceptible condition and evaluate the possible degrading effects of externally generated electrical stimuli upon the unit. The exact susceptibility levels will be established only when susceptibility is below specification limits. The operation and calibration of the test equipment shall conform to vendor's Operating Instructions.

The Test Sample is deemed not to be susceptible when: (1) no more than specified change in indication and (2) no malfunction and no more than specified degradation of data. If susceptibility is established, the results shall be recorded at the test voltage and threshold levels and at random levels between the two. The test procedure must be conducted as outlined herein and the data thus secured for each step recorded on respective Data Sheets. Each step of the procedure should be read in its entirety prior to starting the test.

All tests shall be conducted under test conditions as delineated in MIL-I-26600, paragraph 4.2, and outlined herewith. The test sample and measuring equipment shall be mounted on and bonded to a ground plane installed within a shielded enclosure. The power supplied to the test sample shall be measured at the terminals of the line impedance stabilization network (LISN).

## 2.0 TEST EQUIPMENT (as specified or equivalent):

	•		
Line Impedance Sta	bilization B	ietwork Stoddart	Model 91221-1
Current Probe	•	Stoddart	Model 91550-1
Rod Antenna		Stoddart	Model 92197-3
Antenna Coupler		Stoddart	Model 92198-3
Counter Poise (Gnd	Plane)	Stoddart	Model 92199-3
Dipole Antenna	<b>+</b> ,	Stoddart	Model 91865-2
Dipole Antenna	•	Stoddart	Model 91870-2
Dipole Antenna		Stoddart	Model 91598-2
Horn Antenna	•	Stoddart	Model 91888-1
Horn Antenna	•	· Stoddart	Model 91889-1
Horn Antenna		Stoddart	Model 91890-1
Horn Antenna	•	Stoddart	Model 91891-1
Reflector Antenna		Stoddart	Model 21892-1
RFI Meter		Stoddart	Model: NM 40A
RFI Meter		Stoddart	Model NM 10A .
RFI Meter		Stoddart	Model: NM 22A
RFI Meter	* . -, *	Stoddart	Model NM 30A
RFI Meter	W 4.1	Stoddart	Model NM 52A
RFI Meter	A STATE OF THE STA	Stoddart	Model NM 62A
Signal Generator		Hewlett-Packard	Model HP 200CD
Signal Generator	<b>J</b> .	Hewlett-Packard	Model HP 606A
Signal Generator		Hewlett-Packard	Model HP 608C
Signal Generator		Hewlett-Packard	Model HP 612A
Signal Generator		Hewlett-Packard	Model HP 614A
Signal Generator		Hewlett-Packard	Model HP 616B
Signal Generator		Hewlett-Packard	Model HP 618A
Signal Generator		Hewlett-Packard	Model HP 620A
Digital Voltmeter		Hewlett-Packard	Model HB 405BR
Audio Amplifier, 2	00 watts	McIntosh	Model MI 200A/B
Oscilloscope		Tektronix	Model 555
			1.

HOTE: 'This list includes recommended instrumentation necessary for the performance of the required interference and susceptibility measurements. The actual equipments to be used will appear in the Test Report.

2.1 All equipment used in performance of these tests will be listed as follows:

Test	Para.		Data Sheet Page
Conducted Interference	4.1		
Radiated Interference	4.2	•	8
Conducted Susceptibility	4.3		12
Radiated Susceptibility	4.4		21

#### 3.0 REFERENCE DOCUMENTS:

IESD Document 19-18

Development Flight Instrumentation Environmental Type and Flight Specification (I April 65), Part

TESD Document 19-3

Interference Control Requirements for Spacecraft Equipment (Dec. 64)

- 4.0 PROCEDURE: The test frequency scan shall be made slowly and carefully. All detected signal levels shall be attenuated as required in order to maintain meter indications on scale.
  - A. During the interference tests, the outputs of the multicoder shall be monitored to assure that all outputs are present.
  - B. During the susceptibility tests, the multicoder shall be operated and performance monitored for the following parameters.
    - 4.2.1 Sampling rate; Ref; para. 2.2.1 of ATP.
    - 4.2.2 Input Current; Ref; para. 2.2.2 of ATP.
    - 4.2.3 PAM Noise; Ref. para. 2.2.3 of ATP.
    - 4.2.4 PDM Jitter; Ref. para. 2.2.4 of ATP.
    - 4.2.5 DPDM Amplitude; Ref. para. 2.2.5 of ATP.
    - 4.2.6 Changel Presence; Ref. para. 2.2.6 of ATP.
  - C. Subsequent to the susceptibility tests the multicoder shall be tested for the following performance characteristics: (Record data on data sheet No. 27.)
    - 4.3.1 Sampling rate; Ref. para. 2.3.1 of ATP.
    - 4.3.2 Input Current; Ref. para. 2.3.2 of ATP.
    - 4.3.3 PAM Zero and full scale Output; Ref. para. 2.3.3 of ATP.
    - 4.3.4 PDM Zero and full scale pulse width; Ref. para. 2.3.4 of ATP.
    - 4.3.5 DPDM Output; Ref. para. 2.3.5 of ATP.
    - 4.3.5 . PAM Noise; Ref. para. 2.3.6 of ATP.
    - 4.3.7 PDM Jitter; Ref. para. 2.3.7 of ATP.
    - 4.3.8 Channel Presence; Ref. para. 2.3.8 of ATP.

### 4.1 Conducted Interference

### 4.1.1 LISE

- 4.1.1.1 Connect test equipment and test sample as shown in Figure 1.
- 4.1.1.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.1.1.3 Energize test sample. SCAN frequency range from 150 KC to 25 MC and RECORD the level and frequency of all detected signals on Data Sheet s page 2 and 3.
- 4.1.1.4 De-energize test sample. SCAN frequencies where measurable signals were detected (para. 4:1.1.3) and RECORD the level and frequency of all detected ambient signals on Data Sheets page 2 and 3...
- 4.1.1.5 Photograph test setup.

## 4.1.2 Current Probe (DC Power Leads)

- 4.1.2.1 Connect test equipment and test sample as shown in Figure 2.
- 4.1.2.2 Energize and operate test equipment in accordance with vendor's instruction manual:
- 4.1.2.3 Energize test sample. SCAN frequency range from 30 cps to 150KC and RECORD the level and frequency of all detected signals on Data Sheets page 4 and 5.
  - NOTE: The current probe shall be positioned at the point of maximum interference on the lead being tested. This point shall be located and recorded for each frequency by moving the probe along the lead while monitoring the measuring equipment. The limits established are dependent upon the current carried in the lead. Reference MSC-ASPO-EMI-10A, Figure 4B. This test shall be made on each power lead.
- 4.1.2.4 De-energize test sample. SCAN frequencies where measurable signal levels were detected (para. 4.1.2.3) and RECORD the level and frequency of all detected ambient signals on Data Sheets page 4 and 5.
- 4.1.2.5 Photograph test setup.

# 4.1.3 Current Probe (Signal Leads)

- 4.1.3.1 Connect test equipment and test sample as shown in Figure 3...
- 4.1.3.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.1.3.3 Energize test sample. SCAN frequency range from 15 KC to 25 MC and RECORD the level and frequency of all detected signals on Data Sheets page 6 and 7.
  - MOTE: The current probe shall be positioned at the point of maximum interference on the lead being tested. This point shall be located and recorded for each frequency by moving the probe along the lead while monitoring the measuring equipment. The limits established are depicted in MSC-ASPO-EMI-10A, Figures 4 and 5. This test shall be made on each input signal and inter-connecting lead.
- 4.1.3.4 De-energize test sample. SCAN frequencies where measurable signal levels were detected (para. 4.1.2.3) and RECORD the level and frequency of all detected ambient signals on Data Sheets page 6 and 7.
- 4.1.3.5 Photograph test setup.

# 4.2 Radiated Interference

## 4.2.1 Rod Antenna

- 4.2.1.1 Connect test equipment and test sample as shown in Figure 4.
- 4.2.1.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.2.1.3 Energize test sample. SCAN frequency range from 15 KC to 25 MC and RECORD the level and frequency of all detected signals on Data Sheet page 9 and 10.
- 4.2.1.4 De-energize test sample. SCAN frequencies where measurable signals were detected (para: 4.2.1.3) and RECORD the level and frequency of all detected ambient signals on Data Sheets page 9 and 10.
- 4.2.1.5 Photograph test setup.

### 4.2.2 Dipole Antenna

- 4.2.2.1 Connect test equipment and test sample as shown in Figure 5.
- 4.2.2.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.2.2.3 Energize test sample. SCAN frequency range from 25 MC to 1 GC and RECORD the level and frequency of all detected signals on Data Sheet page 9 and 10.

NOTE: The antenna shall be tuned to 35 mc for the frequency range of 25 - 35 mc and retuned to the proper length twice per octave over the range 35 mc to 1 gc. Whenever interference is detected, the antenna shall be tuned to the exact interference frequency:

- 4.2.2.4 De-emergize test sample. SCAN frequencies where measurable signals were detected (para. 4.2.1.3) and RECORD the level and frequency of all detected ambient signals on Data Sheets page 9 and 10.
- 4.2.2.5 Photograph test setup.

### 4.2.3 Directive Antenna

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- 4.2.3.1 Connect test equipment and test sample as shown in Figure 6.
- 4.2.3.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.2.3.3 Energize test sample. SCAN frequency range from 1 GC to 10 GC and RECORD the level and frequency of all detected signals on Data Sheet pages 11.
  - NOTE: The antenna shall be replaced for one properly tuned for each band of frequencies, i.e., band 1: 1.0 2.3 gc; band 2: 2.3 4.9 gc; band 3: 4.9 7.3 gc; and band 4: 7.3 10.0 gc.
- 4.2.3.4 De-energize test sample. SCAN frequencies where measurable signals were detected (para. 4.2.1.3) and RECORD the level and frequency of all detected embient signals on Data Shepts page 11.
- 4.2.1.5 Photograph test setup.

## 4.3 Conducted Susceptibility

### 4.3.1 Audio Frequency

- 4.3.1.1 Connect test equipment and test sample as shown in Figure 7.
- 4.3.1.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.3.1.3 Energize test sample. Insert 3 volts rms (open circuited) onto each ungrounded power lead. SCAN frequency range 30 cps to 50 kc while monitoring the test sample for proper operation. If the test sample indicates susceptibility, RECORD the frequency and threshold level on Data Sheets page 13 and 14. (Threshold is found by slowly reducing the AC voltage inserted on the power leads until the susceptibility condition is corrected).
- 4.3.1.4 Photograph test setup.

## 4.3.2 Radio Frequency

- 4.3.2.1 Connect test equipment and test sample as shown in Figure 8.
- 4.3.2.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.3.2.3 Energize test sample. Insert 3 volts rms (open circuited) onto each ungrounded power lead. SCAN frequency range 50 cps to 50 kc while monitoring the test sample for proper operation. If the test sample indicates susceptibility, RECORD the frequency and threshold level on Data Sheets page 15 and 16. (Threshold is found by slowly reducing the AC voltage inserted on the power leads until the susceptibility condition is corrected).
- 4.3.2.4 Photograph test setup.
  - 4.3.2.5 Connect test equipment and test sample as shown in Figure 9.
  - 4.3.2.6 Energize and operate test equipment in accordance with vendor's instruction manual.
  - 4.3.2.7 Energize test sample. Insert 100,000 microvolts onto each ungrounded power lead. SCAN frequency range 150 kc to 1 gc with the 100,000 microvolt signal modulated 30% with 400 cps (sine wave) while. monitoring the test sample for proper operation. SCAN frequency range 1.0 10.0 gc with the 100,000: microvolt signal modulated 100% with a 1000 cps square wave. If the test sample indicates susceptibility, RECORD the frequency and threshold level on Data Sheets pages 17 and 18.
  - 4.3.2.8 Photograph test setup.

### 4.3.3 Transient

- 4.3.3.1 Connect test equipment and test sample as shown in Figure 10.
- 4.3.3.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.3.3.3 Energize test sample. Insert positive or negative pulses on each ungrounded power lead for a duration of 2 minutes. The pulses shall be 50 volts in amplitude, 10 microseconds in width and have a repetition rate of 10 PPS. Monitor the test sample for proper operation and verify that no temporary or permenent damage results. If susceptibility is indicated, RECORD the voltage (P-P), polarity and indication on Data Sheet's pages 19 and 20.
- 4.3.3.4 Photograph test setup.

### 4.4 Radiated Susceptibility

### 4.4.1 Loop Antenna

- 4.4.1.1 Connect test equipment and test sample as shown in figure 11.
- 4.4.1.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.4.1.3 Energize test sample. SCAN frequency range 15- 150 kc with a 10,000 microvolt signal modulated 30% with 400 cps.

NOTE: The signal shall not be modulated over the range 15 - 50 kc. The voltage shall be the open-circuited value applied to the antenna terminals.

Monitor the test sample during the scan and if susceptibility is established, RECORD the frequency and threshold level on Data Sheets pages 22 and 23.

NOTE: The loop antenna shall be used as a hand held probe to determine the position of greatest susceptibility.

4.4.1.4 Photograph test setup.

### 4.4.2 Rod Antenna

- 4.4.2.1 Connect test equipment and test sample as shown in figure 12.
- 4.4.2.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.4.2.3 Energize test sample. SCAN frequency range 150 kc to 25 mc with a 100,000 microvolt signal modulated 30% with 400 cps. Monitor the test sample during the scan and if susceptibility is established, RECORD the frequency and threshold level on Data Sheets pages 22 & 24.
- 4.4.2.4 Photograph test setup.

### 4.4.3 Dipole Antenna

- 4.4.3.1 Connect test equipment and test sample as shown in figure 13.
- 4.4.3.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.4.3.3 Energize test sample. SCAN frequency range 25 mc to 1 gc with a 100,000 microvolt signal modulated 30% with 400 cps. Monitor the test sample during the scan and if susceptibility is established, RECORD the frequency and threshold level on Data Sheet s pages 22 and 25.

MOTE: The antenna shall be tuned to 35 mc during the scan from 25 - 35 mc and retuned to the proper length every 50 mc over the remaining frequencies.

4.4.3.4 Photograph test setup.

#### 4.4.4 Directive Antenna

- 4.4.4.1 Connect test equipment and test sample as shown in figure |4.
- 4.4.4.2 Energize and operate test equipment in accordance with vendor's instruction manual.
- 4.4.4.3 Energize test sample. SCAN frequency range 1 10 gc with a 100,000 microvolt signal modulated 100% with a 1000 cycle square wave. Monitor the sample during the scan and if susceptibility is established, RECORD the frequency and threshold level on Data Sheets pages 22 and 26.

NOTE: The antenna shall be replaced for one properly tuned for each band of frequencies, i.e.:

Band 1: 1 - 2.3 gc

Band 2: 2.3 - 4.9 gc

Band 3: 4.9 - 7.3 gc

Band 4: 7.3 - 10.0 gc

4.4.4.4 Photograph test setup.

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DATA SHEFTS

### CONDUCTED INTERFERENCE EQUIPMENT LIST

2.1 List all test equipment used in performance of tests specified in para. 4.1; Care must be taken to supply all of the following information:

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Nomenclature

(Name and Model)

Serial # Hanufacturer Calibration Calibration

Issue	Date	DATA	SHEET 2	OF <u>27</u>	Rev. Date	
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NASA Type	No.		Mfg	r.Model No.	<del></del>	
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Issue Date	DATA SHEET 3	or <u>27</u>	Rev. Date
Type of Test	Conducted Interference Using LISN (BB)	Tested By	

FREQ	METER READING	CORRECTION FACTORS	CORRECTED READING	SPEC LIMIT	ANBIENT	REMARKS
nc	dbuy/mc	db	dbuv/mc	dbuw/mc	dbuv/mc	
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Type	Conducted Interference Type of Test Using Current Probe on Tested By Power Leads (BB)								
FREQ	METER READING	CORRECTION FACTORS	CORRECTED READING	SPEC Limit	AMBIENT	REMARKS			
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Issue	Date	DATA S	HEET	OF <u>27</u>	Rev. Date	
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FREQ	METER READING	CORRECTION FACTORS	CORRECTED READING	SPEC LIMIT	AMBIENT	REMARKS
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## RADIATED INTERFERENCE EQUIPMENT LIST

2.1 List all test equipment used in performance of tests specified in para. 4.2; Care must be taken to supply a. all of the following imformation:

Nomenclature Date of last Date of Next (Name and Model) Serial # Manufacturer Calibration Calibration

Issue Date	DATA SHEET 2	OF 27 Rev. Date
Type of Test	Radiated Interference Using Rod and Dipole Antenna (CW)	Tested By

, FREQ	METER READING	CORRECTION FACTORS	CORRECTED READING	SPEC LIMIT	AMBIENT	REMARKS
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Issue	Date	DATA S	HEET 13	or 27	Rev. Dat	•			
Radiated Interference Using Type of Test Rod and Dipole Antenna Tested By (BB or Pulsed CW)									
FREQ	The same of the sa	CORRECTION FACTORS	CONRECTED READING	SPEC LIMIT	AMBIENT	PENARKS			
mc	dbuv	db	dbuv/mc	dbuv/mc	dbuv/mc				
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Radiated Interference Type of Test Using Directive Antenna Tested By (BB or Pulsed CW)						
FREQ	METER READING	CORRECTION FACTORS		SPEC LIMIT .	AMBLENT	remarks
K0	_dbuy/mc_	. db	dbus/nc	dbue/mc	dbue/mc	
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### CONDUCTED SUSCEPTIBILITY EQUIPMENT LIST

2.1 List all test equipment used in performance of tests specified in para. 4.3. Care must be taken to supply all of the following information:

Nomenclature

(Name and Model) Serial # Manufacturer Calibration Calibration

Issue	Date	DATA S	HEET 13	OF	Rev. Date		
Type	Conducted Susceptibility Type of Test Uning Audio Transformer Tested By						
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# ENVIRONMENTAL TEST DATA SHEET

Conducted Susceptibility Using Audio Transformer

MODEL NO.

DATE

SERIAL NO.	TESTED BY					
	PERFORMANCE DURING EMI TESTS					
PARA. REF.	TEST	DATA				
2.2.1.	Sampling Rate @ 28.0VD	C				
2.2.2.	Input Current @ 28.0VD	C				
2.2.3.	PAM Noise					
2.2.4.	PDM Jitter					
2.2.5.	DPDM Output					
2.2.6.	Channel Presence					
7. <b>*</b> <b>*</b>						

Conducted Suscepticality  Type of Test Using Coil and Condensor Tested By						
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# ENVIRONMENTAL TEST DATA SHEET

Conducted Susceptibility Using Coil And Condenser

	MODEL NO.	DATE		Y House			
	SERIAL NO.	TESTED BY				<u>.</u>	A
•		PERFORMANCE DURING EMI TE	STS.				•
	PARA. REF.	T,EST		DATA	۸		
	2.2.1.	Sampling Rate @ 28.0VDC					-
***	2.2.2.	Input Current @ 28.0VDC			1		
	2.2.3.	PAM Noise	•			·	
	2.2.4.	PDM Jitter					
	2.2.5.	DPDM Output	-				
	2.2.6.	Channel Presence	•	٠.		•	<u>.</u> . _•
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Issue I	Date	DATA SI	17	OF27	Rev. Dat	<b></b>		
Type of	Conducted Susceptibility Type of Test_Radio Frequency Tested By							
rees	TEAET	SUSCEPTIBLE LEVEL				REMARKS		
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## Conducted Susceptibility Radio Frequency

	SERIAL NO.		PERFORMANCE DURING EMIT	TESTS.	•	•
	PARA. REF.		TEST	Į.	DATA	
	2.2.1.		Sampling Rate © 28.0VDC	*		
	2.2.2.		Input Current @ 28.0VDC	·		•
	2.2.3.		PAM Noise	-		
	2.2.4.	3 (1) (4) (4) (4) (4) (4) (4) (4) (4) (4) (4	PDM Jitter			
	2.2.5.		DPDM Output	•		•
•	2.2.6.		Channel Presence	·		

Conducted Susceptibility Type of Test Using Transient Generator Tested By						
OLTS	POLARITY	UNIT OR CIRCUIT				REMARKS
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Conducted Susceptibility Using Transient Generator

SERIAL NO.	TESTED BY	
	PERFORMANCE DURING EMI, TESTS	
PARA. ,. REF.	TEST	DATA
2.2.1.	Sampling Rate @ 28.0VDC	• A 1
2.2.2.	Input Current @ 28.0VDC	
2.2.3.	PAM Noise	
2.2.4.	PDM Jitter	
2.2.5.	DPDM Output	
2.2.6.	Channel Presence	

#### RADIATED SUSCEPTIBILITY EQUIPMENT LIST

2.1 List all test equipment used in performance of tests specified in para. 4.4: Care must be taken to supply all of the following information:

Nomenclature

(Name and Model) Serial # Manufacturer Calibration Calibration

Radiated Susceptibility  Type of Test Using Loop, Rod, Divole and Tested By  Directive Antennas  FDEO SCAN THRESHOLD SPEC ANTENNA REMARKS							
FREQ	SCAN LEVEL	THRESHOLD LEVEL	SPEC LIMIT	ANTENNA		REMARKS	
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Radiated Susceptibility Using Loop Antenna

	MODEL NO.		DATE				
	SERIAL NO.		TESTED BY_			- •	
		PERFORM	ANCE DURING EMI T	TESTS		•	•
	PARA. REF.		TEST	D	ATA .		
	2.2.1.	Samplin	Rate @ 28.0VDC	-	*		- 1 . #
	2.2.2.		urrent @ 28.0VDC		•		
	2.2.4.	PAM Noi PDM Jit					
- -	2.2.5.	DPDM Ou	tput				•
	2.2.6.	Channel	Presence			·	•

Radiated Susceptibility Using Rod Antenna

	SERIAL NO.	TESTED BY				•
		PERFORMANCE DURING EMI T	ESTS		•	•
	PARA. REF.	TEST	•	DATA .		
•	2.2.1.	Sampling Rate @ 28.0VDC				· · · · · · · · · · · · · · · · · · ·
	2.2.2.	Input Current @ 28.0VDC	· · · · · ·			
	2.2.3.	PAM Noise	•			•
	2.2.4.	PDM Jitter	-			
	2.2.5.	DPDM Output	*****			:
;	2.2.6.	Channel Presence	·			•
		•		•		

Radiated Susceptibility Using Dipole Antenna

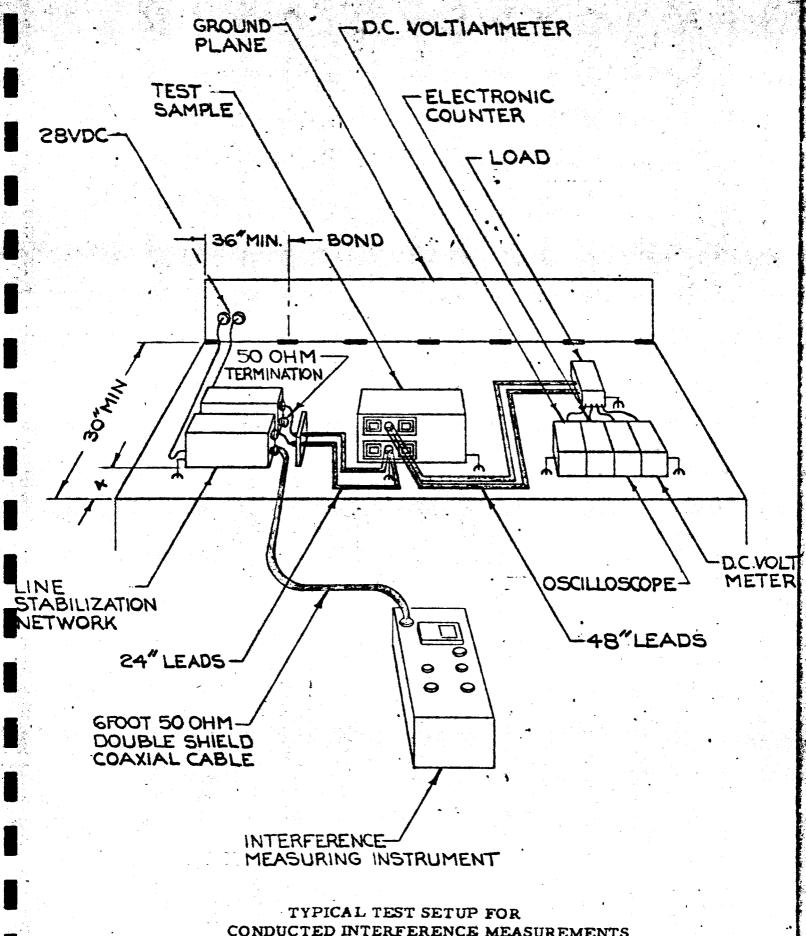
	SERIAL NO.		TESTED	вү		
T		PE	PERFORMANCE DURING EMI TESTS			
	PARA. REF.		TEST		DATA .	
	2.2.1.	Sŧ	ampling Rate © 28.0	VDC	•	
	2.2.2.		nput Current @ 28.0	VDC		
	2.2.3.	P	AM Noise	•		
	2.2.4.	P	DM Jitter	-		
	2.2.5.	D	PDM Output	· · · · ·	•	· · · · · · · · · · · · · · · · · · ·
	2.2.6.	C	hannel Presence	-		•
			• ,			

Rad	iated Su	sceptibility Using Direc	tive	Antenna		
MODEL NO.		DATE		· · · · · · · · · · · · · · · · · · ·		
SERIAL NO.		TESTED BY				
	e well by	PERFORMANCE DURING EMI	TE <b>ST</b> S	. 1 4 j. 26 j. G		
PARA - REF -		TEST	:	DATA		
2.2.1.		Sampling Rate @ 28.0VDC				
2.2.2.		Input Current @ 28.0VDC			·	
2.2.3.		PAM Noise			N 🖟 sa 🖫 🧸	
2.2.4.		PDN Jitter	v 1 •			- 1 × 1 × 1 × 1 × 1 × 1 × 1 × 1 × 1 × 1
2.2.5.	•	DPDM Output				<b>-</b> .
2.2.6.		Channel Presence .			, ,	
					**.	•

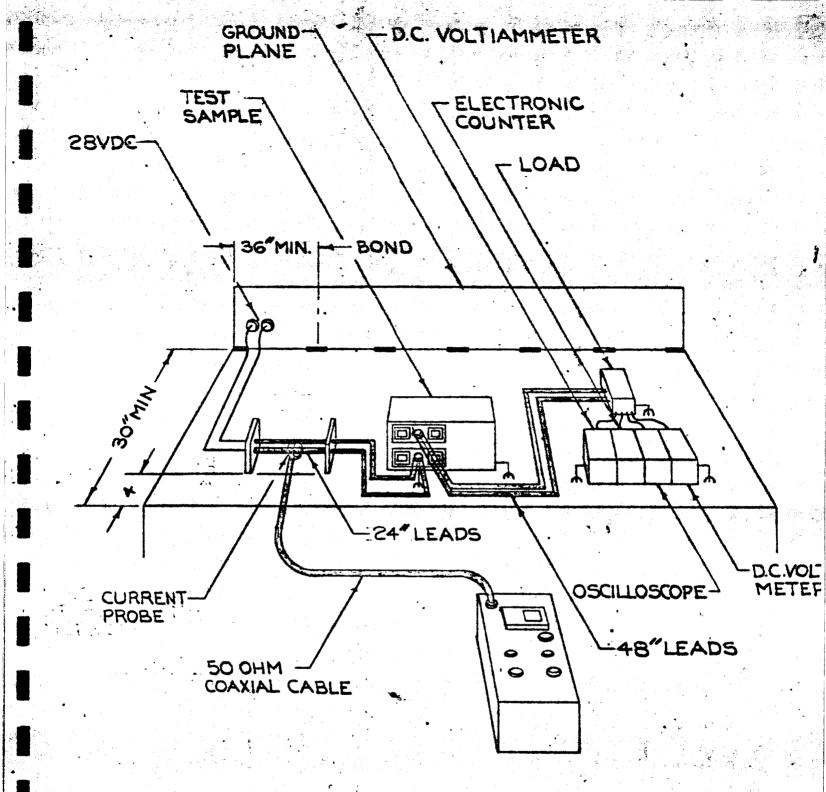
MODEL	NO	DATE			
SERIAL		TESTED BY			
	PERFORMANCE DATA	AFTER EMI	TESTS		
PARA. REF.	TEST		DATA		
2.3.1	Sampling Rate @ 22.0 VDC	•			
•	@ 24.0 VDC				
	@ 28.0 VDC				
&*	@ 32.0 VDC	• •	•		
	@ 28.0 VDC	٠,			
2.3.2	Input Current @ 28.0 VDC				
2.3.3	PAM Output #MP# Zero				
,	Full Scale				
2.3.4	PDM Pulse Width: Zero	•	. 1.		
•	Full Scale				
2.3.5	DPDM Amplitude				
2.3.6	PAM Noise	•			
2.3.7	PDM Jitter	**************************************	•		
2,3.8	Channel Presence				

6.0

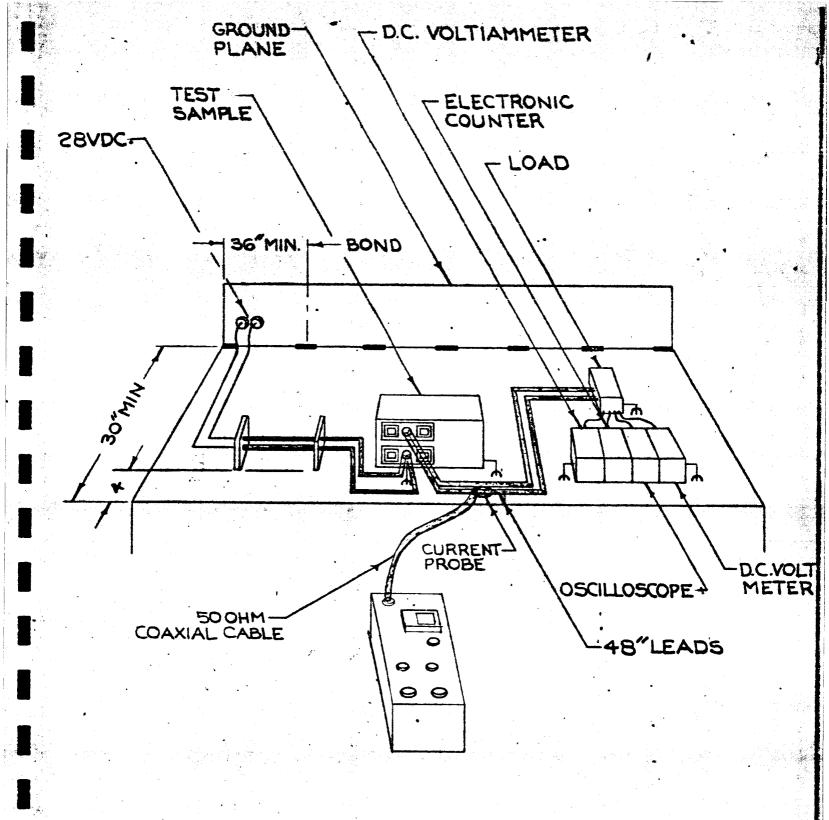
DRAWINGS



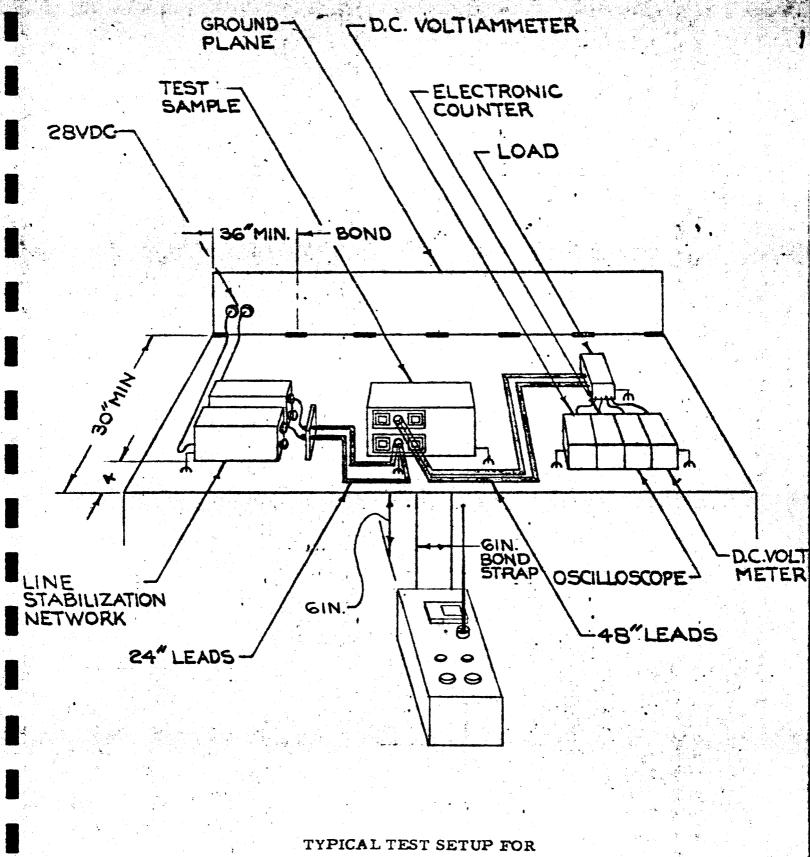
CONDUCTED INTERFERENCE MEASUREMENTS



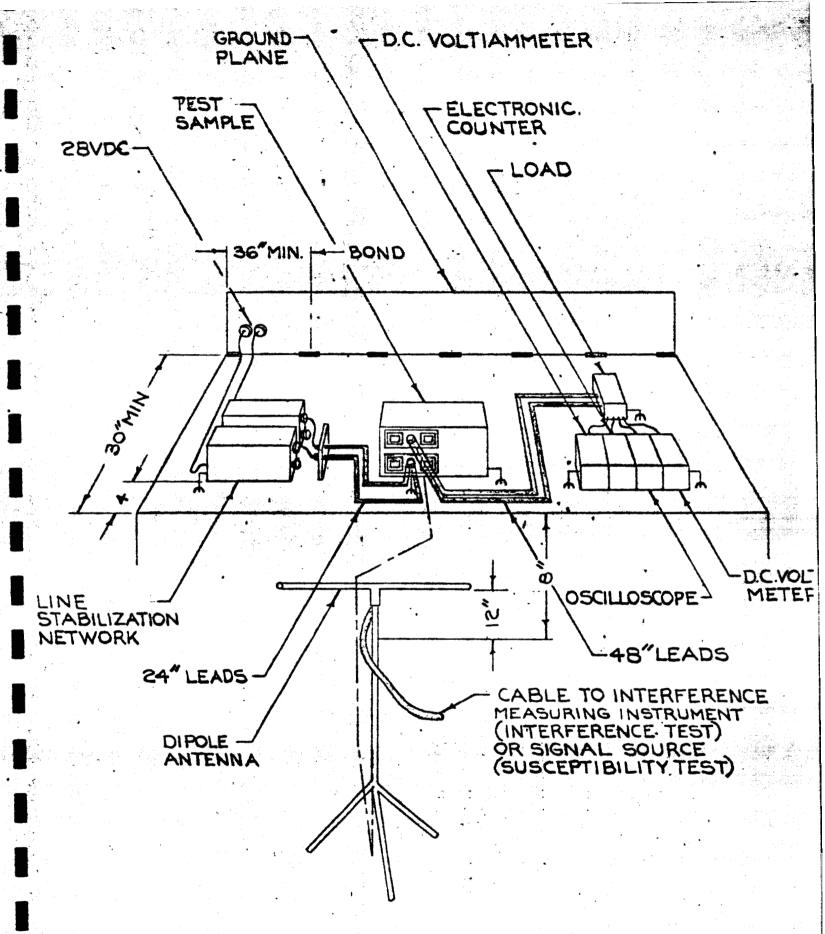
TYPICAL TEST SETUP FOR
CONDUCTED INTEREERENCE MEASUREMENTS
USING CURRENT PROBE - POWER LEADS



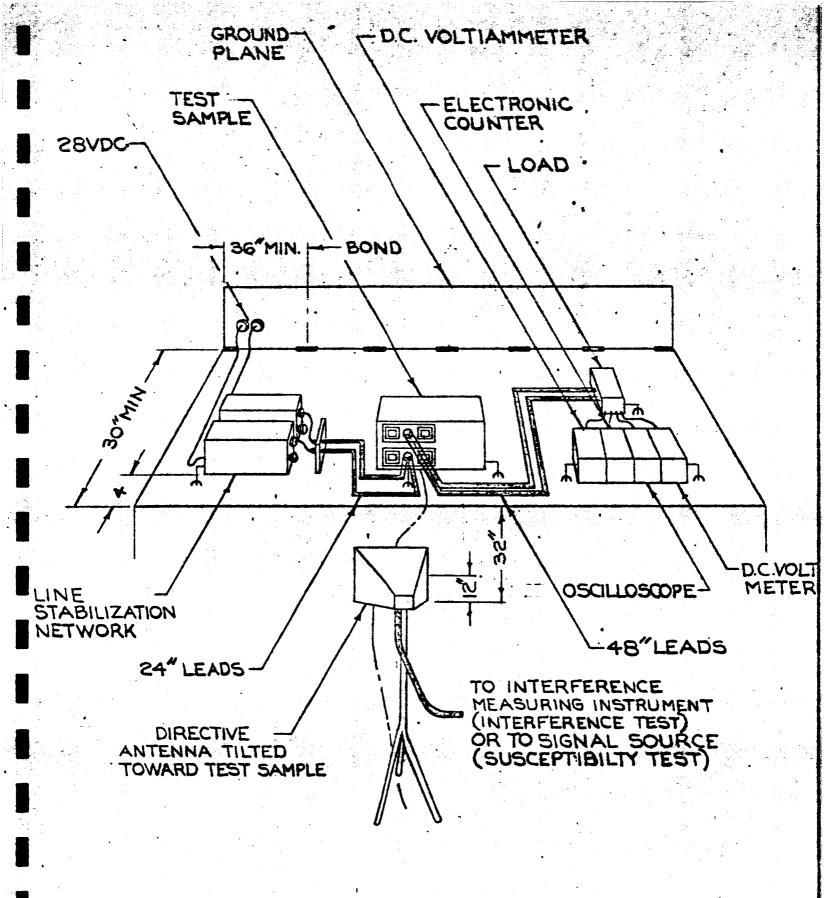
TYPICAL TEST SETUP FOR CONDUCTED INTERFERENCE MEASUREMENTS USING CURRENT PROBE - SIGNAL LEADS



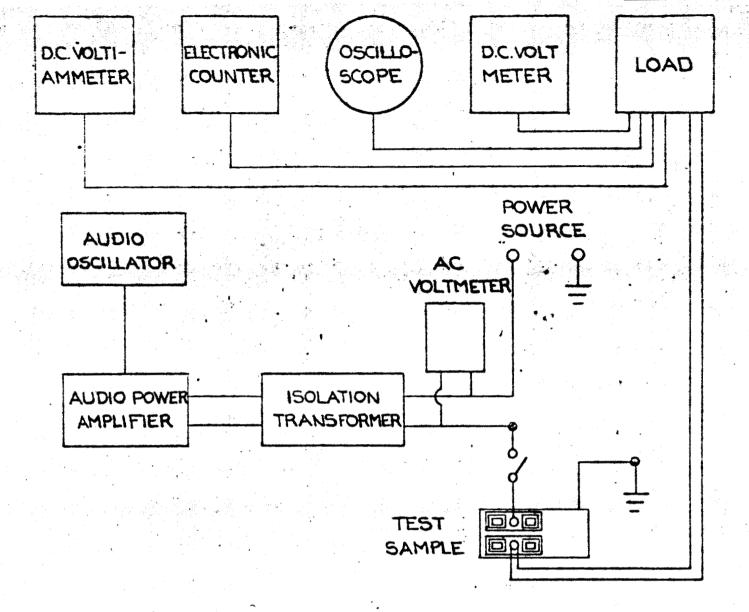
TYPICAL TEST SETUP FOR RADIATED MEASUREMENTS (ROD ANTENNA)



TYPICAL TEST SETUP FOR RADIATED MEAŞUREMENTS (DIPOLE ANTENNA)



TYPICAL TEST SETUP FOR RADIATED MEASUREMENTS ( DIRECTIVE ANTENNA)

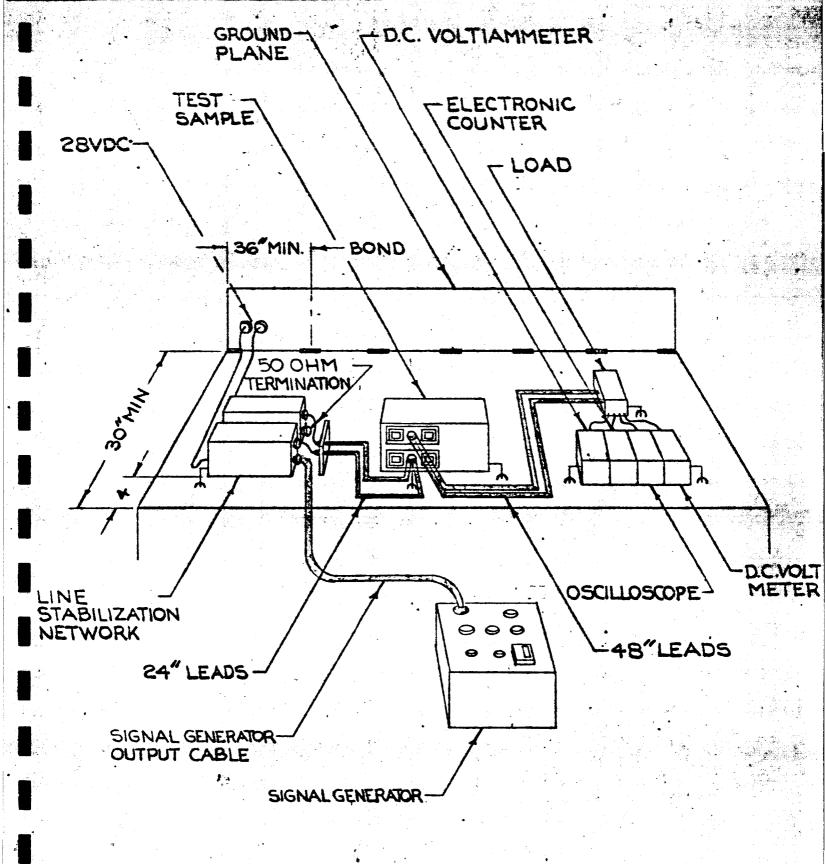


- 1. Audio amplifier shall be 30 50 watts and shall have a low impedance output of 5 ohms or less.
- 2. Transformer shall carry all currents without saturation.

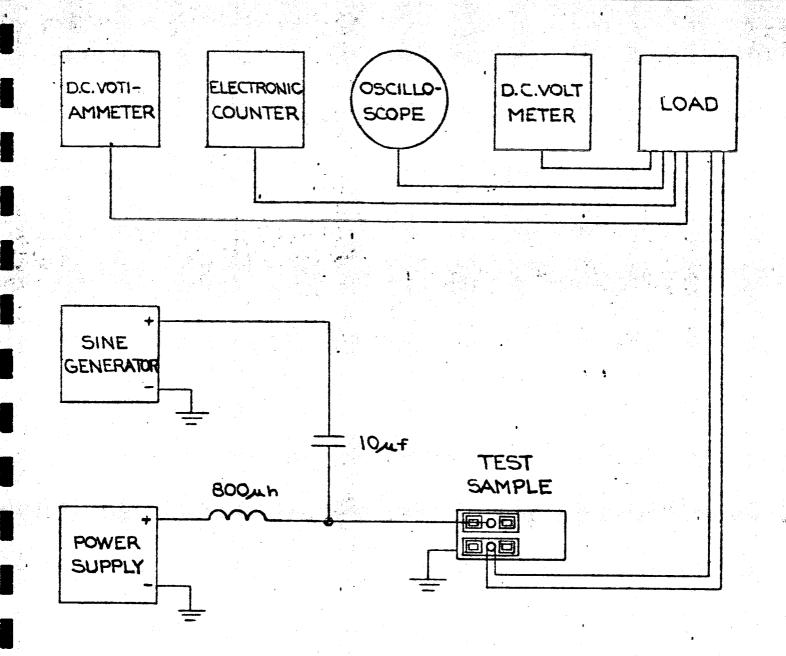
Turns ratio 
$$\frac{\text{primary}}{\text{secondary}} = \frac{2}{1}$$
.

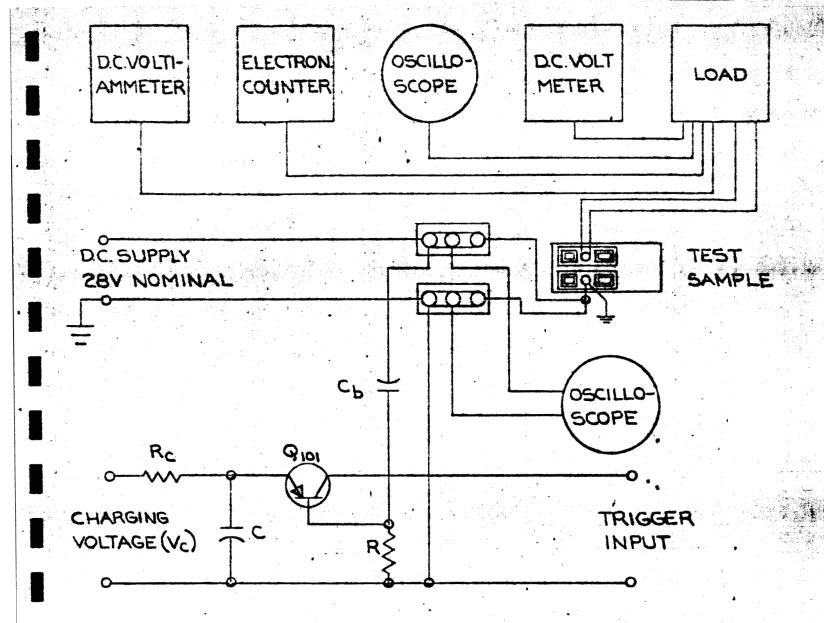
- 3. Series capacitor on AC voltmeter shall have reactance not greater than 1/10 meter impedance.
- 4. The 3 volts AC signal is an open circuit voltage and is measured across the secondary of the isolation transformer, while the test sample and power source are disconnected.

AF SUSCEPTIBILITY TEST SETUP



RF SUSCEPTIBILITY TEST SETUP (CONDUCTED)





#### TRIGGER SPECIFICATIONS:

Duration: Less than 20 microseconds

Rate: 10 PPS

Amplitude: 50 to 85 milliamps into zero resistance load

Rise Time: 0.5 microsecond or less

R (Stabilizing Resistor) = nominal 5 ohms, carbon,  $\frac{1}{2}$  watt

C = nominal one mfd, paper, 600 WVDC

R<sub>c</sub> = nominal 10 k, carbon, one watt

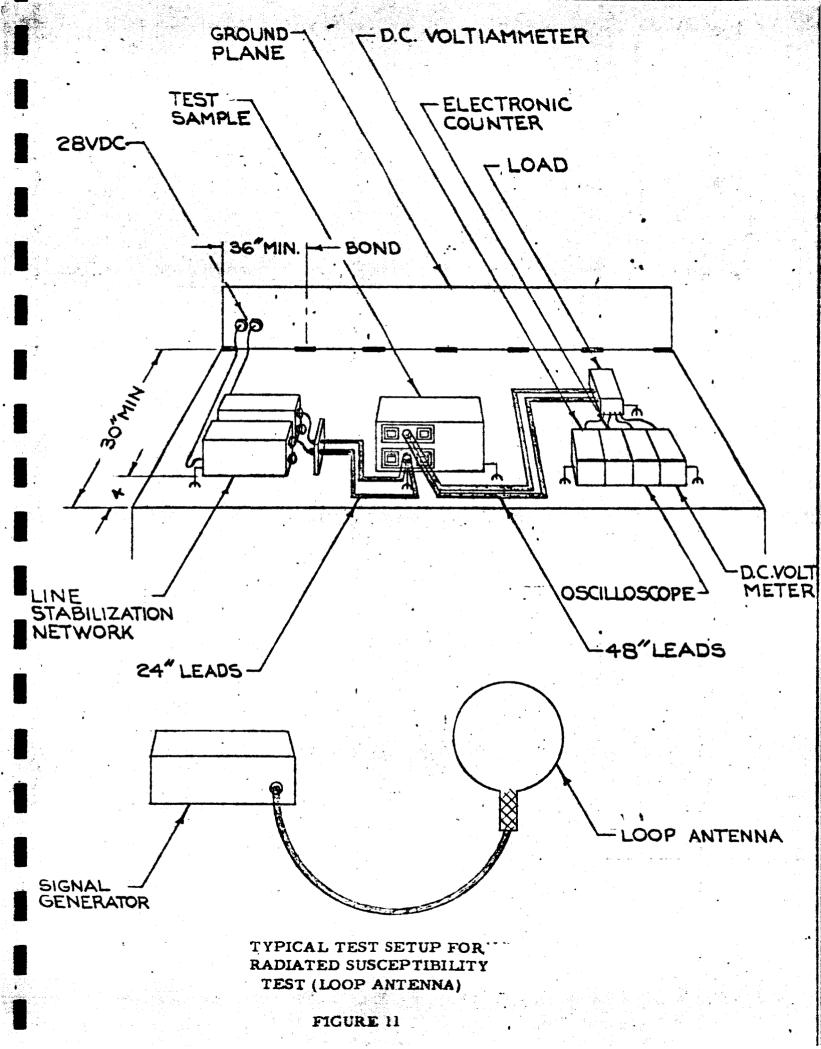
 $C_{b} = 10 \text{ mfd, paper, } 200 \text{ WVDC}$ 

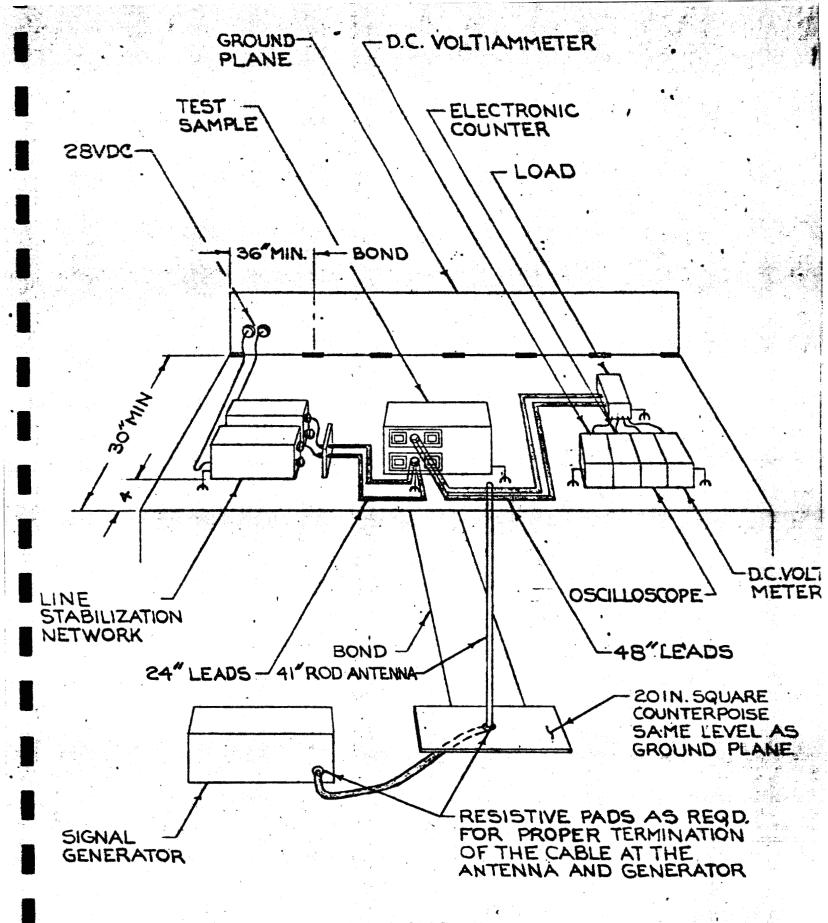
Q<sub>101</sub> = silicon controlled recitfier, minimum ratings:

10 amps, 200 volts. (General Electric ZJ39L or equivalent)

V = DC source, 100 to 150 volts (100 volts nominal), 15 MA

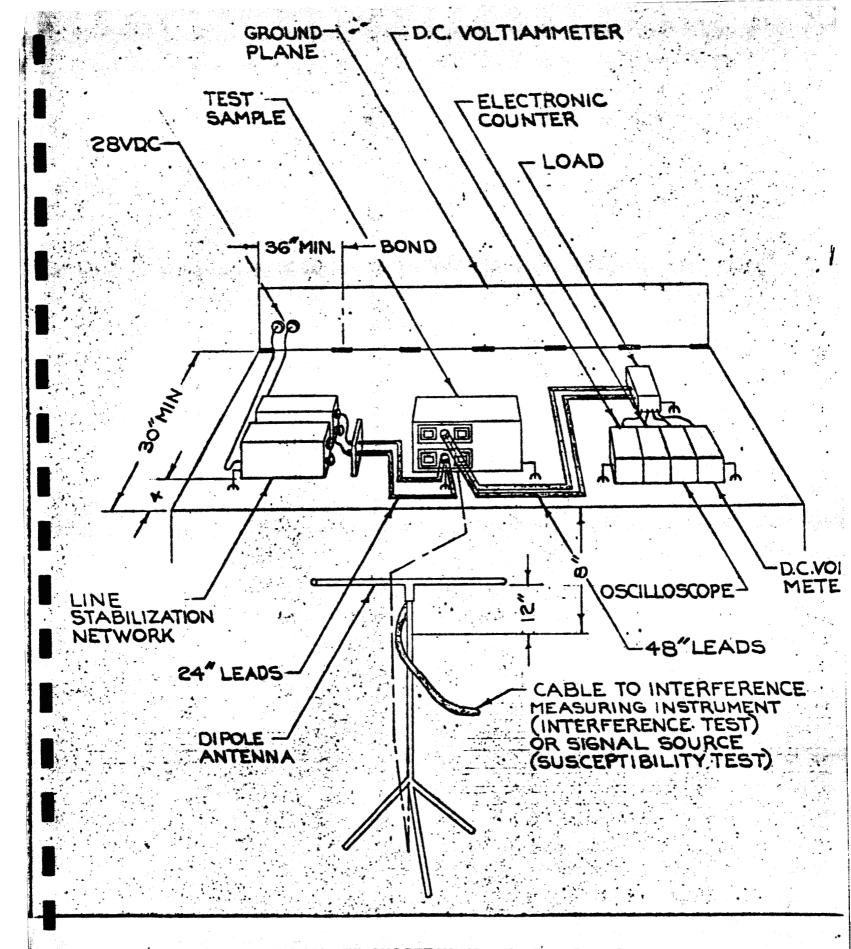
# CONDUCTED TRANSIENT SUSCEPTIBILITY ARRANGEMENT



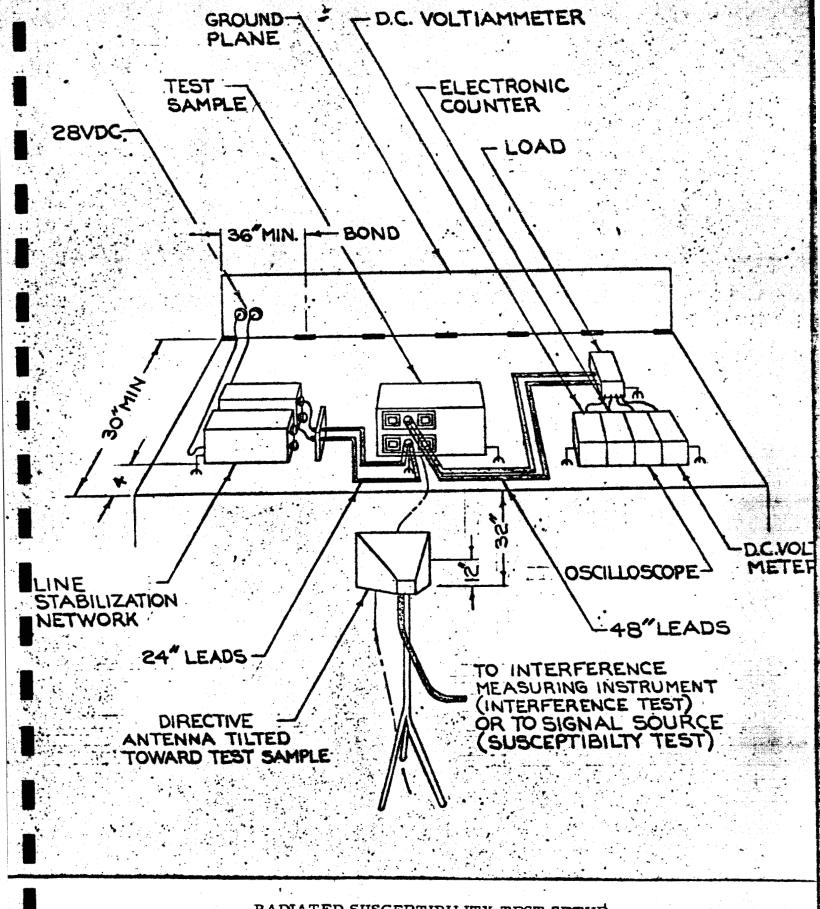


RADIATED SUSCEPTIBILITY
TEST SETUP (ROD ANTENNA)

1 4 .



RADIATED SUSCEPTIBILITY TEST SETUP (DIPOLE ANTENNA)



RADIATED SUSCEPTIBILITY TEST SETUP (DIRECTIVE ANTENNA)